

INFORMATION DISCLOSURE CITATION PTO-1449			Atty Docket: 061450/0304606 FID-101-D2		Serial No. to be assigned	
			Applicant: S. Prakash			
Submitted: July 3, 2003			Filing Date: Herewith		Prior Group Art Unit: 2856	
U.S. PATENT APPLICATIONS						
EXAMINER'S INITIALS	PATENT NO.	DATE	NAME	CLASS	SUBCLASS	FILING DATE
<i>RJ</i>	5,723,981	03 Mar 1998	Hellemans et al.	324	719	06/25/96
↓	5,992,226	11/1999	Green et al.	73	105	
↓	5,763,768	06/1998	Henderson, et al.	73	105	
FOREIGN PATENT DOCUMENTS						
EXAMINER'S INITIALS	PATENT NO.	DATE	COUNTRY	CLASS	SUBCLASS	Translation
						Yes
OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)						
<i>RJ</i>	De Wolf, et al. "Lateral and vertical dopant profiling in semiconductors by atomic force microscopy using conducting tops" (J. Vac. Sci. Tech. A 13(3), May/June 1995, pp. 1699-1704)					
EXAMINER	<i>R A Z V I S</i>		DATE CONSIDERED	# 5-17-04		

EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.